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<b>Notice of References Cited</b>	Application/Control No. <div style="text-align: center;">10/060,058</div>		Applicant(s)/Patent Under Reexam <div style="text-align: center;">Ueno et al.</div>	
	Examiner <div style="text-align: center;">Tu M. Nguyen</div>		Art Unit <div style="text-align: center;">3748</div>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>	
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B	5,396,764	3/1995	Rao et al.	60	287
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**NON-PATENT DOCUMENTS**

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